

Supplemental data:

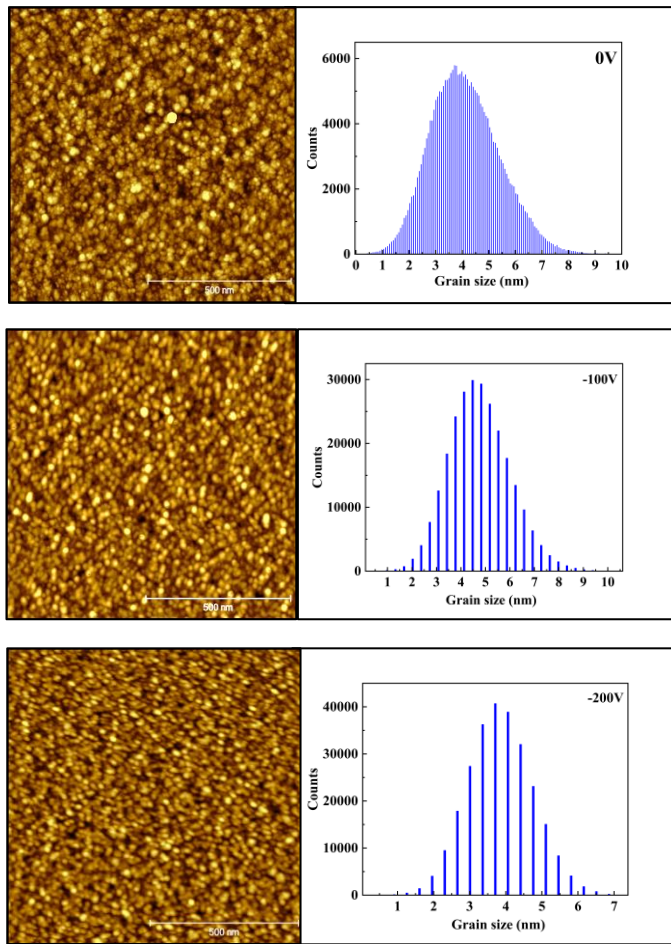


Fig: AFM topography and respective grain size distribution histogram (nm) images of 0V, -100V and -200V bias.

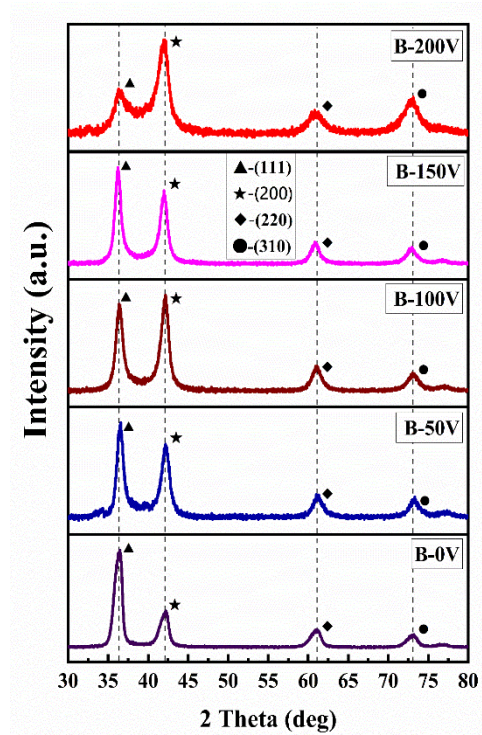


Fig: XRD diffractogram stacking of all samples.

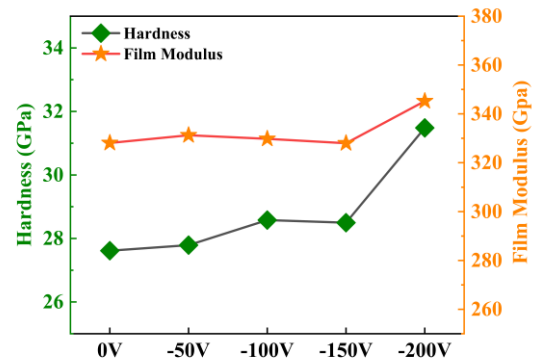


Fig. Hardness and Film modulus variation with Bias voltage.